

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE 1. 103 .: 09/833,084 Confirm

Application No.:

First Named

Ibrahim Abdulhalim et al.

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Inventor:

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MISALIGNMENT

PROUP 7 2003

Assignee:

San Francisco, California March 27, 2003

COMMISSIONER FOR PATENTS Washington, D. C. 20231

## PRELIMINARY AMENDMENT

Dear Sir:

Prior to examination, please amend the above-referenced application as follows:

## IN THE CLAIMS:

Please add new claims 55-84 as follows:

- 55. (New) A method for controlling layers alignment in a multi-layer sample, the method comprising the steps of:
- providing a measurement site including two regions located one above the other in two different layers, respectively, said regions containing patterned structures of certain known periodicity;
- illuminating said site with electromagnetic radiation and detecting a parameter of radiation diffracted from the patterned structures indicative of a lateral shift between the patterned structures; and
- analyzing said parameter to determine an existing lateral shift between the layers.

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